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Authors Lum, Yanwei Ager, Joel W

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Stability of residual oxides in oxide-derived Cu catalysts for electrochemical CO₂ reduction investigated with ¹⁸O labeling

Yanwei Lum and Joel W. Ager*

ChemSusChem

CommunicationS Abstract: Oxide-derived (OD) Cu catalysts have high selectivity towards the formation of multi-carbon products (C_2/C_3) for aqueous electrochemical CO_2 reduction (CO_2R) . It has been proposed that a large fraction of the initial oxide can be surprisingly resistant to reduction and that these residual oxides play a crucial role in promoting the formation of C_2/C_3 products. We investigate the stability of residual oxides by synthesizing ¹⁸O enriched OD Cu catalysts and testing them for CO2R. These catalysts maintain a high selectivity towards C₂/C₃ products (~60%) for up to 5h in 0.1 M KHCO3 at -1.0 V vs RHE. However, secondary ion mass spectrometry measurements show that only a small fraction (< 1%) of the original ¹⁸O content remains, showing that residual oxides are not present in significant amounts during CO₂R. Furthermore, we show that OD Cu reoxidizes rapidly in the absence of a reducing potential, which could compromise the accuracy of exsitu methods for determining the true oxygen content.

Electrochemical reduction of CO_2 (CO_2R) into chemical fuels and feedstock, powered by renewable electrical energy has been proposed as a strategy to mitigate rising greenhouse gas emissions. ^[1–3] Two main challenges in this area of research are improving the product selectivity and reducing the overpotentials required to drive CO_2R .^[2,4,5] "Oxide-derived" Cu (OD Cu) catalysts have attracted much attention because they exhibit higher selectivity towards potentially valuable multi-carbon products (e.g. ethanol and ethylene) with lower overpotential requirements.^[6–13]

OD Cu catalysts are formed by oxidizing Cu an subsequently reducing it. Recently, it has been proposed the residual oxides are responsible for its remarkable catalysts properties.^[11–13] Using *ex-situ* energy dispersive X-ray spectroscopy (EDS), Cuenya and co-workers reported that a large fraction of the initial oxide can be resistant to reduction even under strongly reducing potentials typically used for CO₂R. ^[11,12] They proposed that the presence of Cu⁺ on the surface was important for the formation of C₂/C₃ products.^[12] Musule and co-workers studied an OD Cu catalyst with ambient pressure ray photoelectron spectroscopy (XPS) and electron energy spectroscopy (EELS) and they found a small amount of oxygen

[*] Y. Lum and Prof. J.W. Ager

Joint Center for Artificial Photosynthesis and Materials Sciences Division, Lawrence Berkeley National Labor vry, California 94720, United States

Department of Materials Sciel California, Berkeley, California 9

E-mail: jwager@lbl.gov

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versity of

residing in the subsurface, possibly modifying the electron structure of the catalyst and creating active sites will higher CO binding energy.^[14]

First principles calculations performed by ard and coworkers found that the presence en in the ırface would generate a mix of Cu⁺ a Cu⁰ on the urface. These could then work with adsorbed Ó and aid in C activation by O2R.^[15] In a forming chemisorbed CO₂, which is the first step o separate report, they investigate a partially re ced copper ions.^[16] They oxide matrix consisting of and Cu mix showed that Cu⁺ and Cu⁺ ynergistically to ions promote CO dimerization an ppress C_1 pathways, thereby boosting catalyst selectivity.

However, a few ects of this erging picture of the role of residual oxides in a ctivity of OD Cu are puzzling. (1) Cu nanomaterials have been shown to readily oxidize, which could create difficulties in performing accurate exion of the sygen content.^[17,18] (2) Moisture and own to suse corrosion (oxidation) of Cu and situ quantification of the oxvgen are exposure to b h is difficult to avoid. Corrosion might also be exacerbated in a orous, high surface area material such as OD Cu. (3) OD Cu n sesses a high density of grain boundaries, elerate the oxidation process by serving whic pathways where diffusion can occur as nucleation sites a at a faster rate.[19-23] It is therefore possible that upon removal of reducing potential, Cu rapidly reoxidizes and as a result, the O content characterized *ex-situ* would not be representative of the se during CO₂R. actua

address hese concerns, we employed ¹⁸O isotope r to confirm the presence/absence of residual ing in or Cu during CO₂R. ¹⁸O enriched OD Cu catalysts s in O sized by oxidation/reduction cycling in H₂¹⁸O e procedure of Nilsson and co-workers (see SI for full followi details).^[27] These OD Cu catalysts (OD18 Cu) were then tested R for various times and the residual ¹⁸O content was for ed ex-situ using secondary ion-mass spectrometry ana S). This *ex-situ* method allows us to determine what the "*in-*" oxygen content of the catalyst is during operation as any ubsequent reoxidation of the catalyst would not result in ¹⁸O enrichment above the natural isotopic abundance of 0.2 atomic %.

Figure 1a shows the electrochemical oxidation and reduction process used to generate OD18 Cu by sweeping to an anodic potential and then to a cathodic potential in an electrolyte consisting of 0.1 M KHCO₃ and 32 mM of KCl in H₂¹⁸O. Working electrodes were 1 μ m thick Cu films deposited on Si, and oxidation results in formation of Cu₂¹⁸O nanocubes on the surface. Reduction results in loss of the cubical morphology and formation of a porous oxide-derived layer (roughness factor ~22), which is approximately 100 nm thick. Additional characterization, including electroactive surface area, additional SEM images, Raman spectroscopy, x-ray photoelectron

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spectroscopy and x-ray diffraction are available in the SI (Figures S1 to S8).

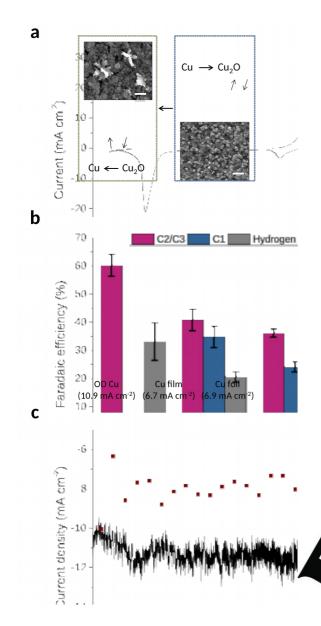


Figure 1. (a) Electrochemical oxidation and reduction procedure for generating OD18 Cu. The blue box highlights the oxidation stage and the green box highlights the reduction stage. SEM images are from as insets (scale bars: $0.5 \ \mu\text{m}$) (b) Faradaic efficiency to C_2/C_3 , C_1 and C_1 for OD Cu, Cu film and Cu foil (70 min tests). Average current densities a up in parenthesis (full data in Tables S2 to S5). (c) 5 h long CO₂R with OD Cu Graph shows current density (black line) and faradaic efficiency to ethylen (red squares) vs time. See Figure S9 for faradaic efficiency to other gas products. Error bars are standard deviations from 3 comperiments.

The product distributions obtained by operating OD18 Cu catalysts at -1.0 V vs RHE with CO2 saturated 0.1 M KHCO3 in H₂¹⁶O electrolyte for 70 mins are shown in Figure 1b along with results from the unmodified Cu film and a Cu foil. As expected, OD18 Cu has a higher selectivity towards C₂/C₃ products (60.1%) and lower selectivity towards C1 products (6.5%) relative to planar Cu controls. Values obtained here are in good agreement with what has been reported for OD Cu in the literature (Table S6). During long-term testing b) the gas product distribution was relatively stable, with bylene selectivity of ~34% throughout (Figures 1c and S9). Next, CO₂R was performed under identical con ons for mins, 30 mins, 1 hr and 5 hrs with fres OD18 Cu. aple After CO₂R, the samples were rinsed with cop amounts of DI

water, dried and then quickly stored $a N_2 g$ box. The residual ¹⁸O and ¹⁶O contents of samples l as a as w Se freshly prepared sample (0 mins vere determin ex-situ using SIMS (Figure 2). Also, a co ol sample was repared by oxidation and reduction in H₂¹⁶ lectrolyte and te ed for CO₂R for 1 hr (OD16 Cu 1 hr).

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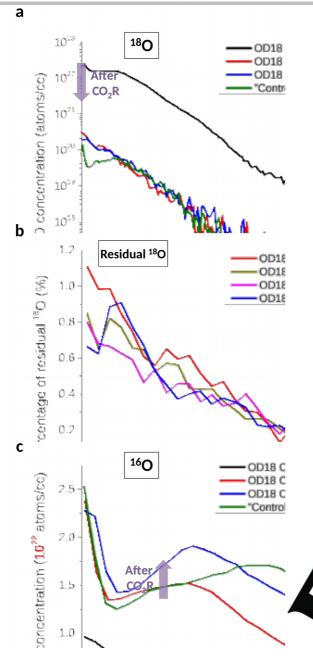


Figure 2. (a) ¹⁸O and (c) ¹⁶O content of OD Cu catalysts with different CO_2R durations measured by SIMS. Note the different scales in (a) at (c). For ease of viewing, the results for 30 mins and 1 hour are omitted in the figure s 17 and S18. (b) shows the percentage with that remains in OD18 Cu after CO_2R (see SI for calculation details)

ins has ¹⁸O As seen from Figure 2a, the OD18 content on the order of 10²² atom CC. which same order of magnitude as the atom lensity of Cu hq successful incorporation of ¹⁸O into эe catalyst stru ture. ie ¹⁸O content drops However, after CO₂R has been carried ou the initial ¹⁸O that drastically. Figure 2b shows the percentage remains after CO₂R (details n the top ~100 rived layer). nm layer (estimated thickne al ¹⁸O remains after CO₂R Surprisingly, only <1% of the or and, in fact, the ¹⁸O content dr to the same order of magnitude as the g Cu 1 hr, which was not OD enriched with ¹⁸O the control sample is

due to its natural abundance of 0.2 atomic %.) This means that the oxide layer is completely reduced, as would be expected since the applied potential typical of CO_2R is >1 V negative of the standard reduction potential of Cu_2O . There therefore cannot be a large concentration of oxygen remaining in the catalyst under CO_2R conditions. Another possibility is that during CO_2R , ¹⁸O atoms that leave as a result of reduction are replaced instantly via oxidation, with ¹⁶O taking its place. However this is unlikely as the oxidation step is thermodynamic unfavorable because of the highly reducing potentials applied.

Intriguingly even after CO₂R, the ¹⁶O content in does not change and actually increases (Figure 20 h fact, contents after CO₂R are on the of atoms/cc, suggesting that samples have been heavily ed. However, in our experimental process, care, taken ire that exposure to ambient air was ninimal as DOSS é. We therefore considered the possil that reoxid n of OD Cu occurs rapidly, as soon as the r ucing potential is rned off. Insitu Raman spectroscopy meas ments by Yeo a co-workers on Cu₂O films revealed that app ion of a pote al of -0.99 V vs RHE resulted in loss of . Raman peaks. char and they concluded that con e reduction to metallic Cu⁰ had taken place.^[6] Surprisingly, of the potential was removed, Cu₂O peaks began to appear aga fter 60 s and bv 120 s had become very distinct, d reoxidation of OD Cu had taken place. In this work, In-su man spectroscopy was also carried out (Figure S10) and similar observations were made.

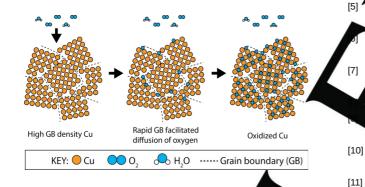
To furthe mphasize e rapid oxidation of OD Cu. a freshly prepared OD Cu sample was soaked in H₂¹⁸O (with 0.1 M KHCO₃) for 3 r as and then rinsed immediately with DI water. nts revealed that the ¹⁸O content in this SIMS measuren le trace) indeed rises by an order of samr tigate the reoxidation process, CO₂R mag was carried out on an C 16 Cu sample in H₂¹⁸O electrolyte (0.1 (HCO₃) at -1.0 V vs RHE for 3 mins. This sample was then vashed with DI water and the ¹⁸O content in this sample was analyzed ex-situ using SIMS (Figure 3, red trace). simila gly, this s hple showed a very high incorporation of ¹⁸O, Start hs on the order of ~10²² atoms/cc, meaning that wit oncentra of reoxidation had occurred. We emphasize that rge degre ent is not simply due to trapped H₂¹⁸O in these co lysts. This is evidenced by Raman peak shifts of porot Cu₂O consistent with isotopic substitution (Figure S11a). Taken togener, all these results highlight the difficulty of ex-situ rements of the oxygen content, since OD Cu can be mea y reoxidized. rai

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$10^{10} \text{ Control}^{18} \text{ Control}^{-18} \text{ OD16 Cl} \text{ OD16 C$

Figure 3. ¹⁸O content in OD16 Cu 1 hr, OD16 Cu with CO₂R for 3 mins in $H_2^{18}O$ electrolyte and OD16 Cu that was soaked in $H_2^{18}O$ for 3 mins. The ¹⁶O content was also analyzed (Figure S11b).

Finally, we consider the reasons for the rapid reoxidation of OD Cu. Firstly, Cu nanomaterials are known to be easily oxidized due to numerous highly reactive undercoordinated atoms on the surface.^[18] Secondly, previous studies have shown that grain boundaries can act as nucleation sites for oxide growth as well as provide channels diffusion can take place at a faster rate (compared to diffusion through the bulk lattice).^[19–23] OD Cu has a high density of grain boundaries,^[8,25,26] which could explain why OD Cu can reoxidize so quickly via exposure to ambient air and moisture (see Schematic 1). Comparatively, Cu with fewer grain boundaries (Cu film) does not oxidize as quickly, as illustrated by our Cu Auger LMM measurements (Figure S8).



Scheme 1. Rapid reoxidation of OD Cu occurs because oxygen oxide nucleation can be facilitated by grain boundaries.

In conclusion, the stability ides was **▲**Of ¹⁸O enriched investigated by ¹⁸O isotope labeling rived Cu catalysts were synthesized and *ith* 2R was perfor them. The residual ¹⁸O content was the analyzed ex-site with original ¹⁸O content SIMS and it was found that only <1% of t remained in the samples. We therefore co ude that residual oxides are unstable in our atalvsts during CO₂R. We believe that the t selectivity gh exhibited by these catalysts is ma likely due to a high density of grain boundaries As previously posed by Kanan and coworkers^[26,27]. We catalysts can rapidly reoxidize due, possibly grain boundaries present in the material. The rapid reoxidation process could compromise the accuracy of *ex-situ* methods for determining the true oxygen content of the catalyst during CO_2R conditions.

Acknowledgements

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- C. Graves, S. D. Luces and Modernen, K. S. Lackner, *Renew.* Sustain. Energy Rev. 2011, 15, 1–24
- Y. Hori, in *Mod. Asp. Electrochem. SE* 3 (Eds.: C. Vayenas, R. White M. Gamboa-Alucco), Springer New York, New York, NY, 2001 (p. 89–189).
- J.-P. Johns, G. K. S. Prakash, G. A. Olah, *Isr. J. Chem.* 2014, 54, 1451–144
- [4] K. P. Kuhl, R. Cave, D. N. Abram, T. F. Jaramillo, Energy Environ.
 - K. P. Kuhl, T. Hassende, E. R. Cave, D. N. Abram, J. Kibsgaard, T. F. Jaramillo, *J. Am. Chem. Soc.* **2014**, *136*, 14107–14113.
 - D. Ren, Y. Deng, A. D. Handoko, C. S. Chen, S. Malkhandi, B. S. Yeo, ACS Catal. **2015**, 5, 2814–2821.

M. Ma, K. Janashvili, W. A. Smith, *Angew. Chemie Int. Ed.* **2016**, 55, 6680 5684.

C. W. J, M. W. Kanan, *J. Am. Chem. Soc.* **2012**, *134*, 7231–7234. R. M.S, R. Kortlever, A. Milbrat, M. T. M. Koper, G. Mul, J.

rusaitis, Phys. Chem. Chem. Phys. **2014**, 16, 12194–12201.

Lum, B. Yue, P. Lobaccaro, A. T. Bell, J. W. Ager, J. Phys. Chem.
 C 2017, 121, 14191–14203.

D. Gao, I. Zegkinoglou, N. J. Divins, F. Scholten, I. Sinev, P. Grosse,
B. Roldan Cuenya, ACS Nano 2017, 11, 4825–4831.

H. Mistry, A. S. A. S. Varela, C. S. C. S. Bonifacio, I. Zegkinoglou, I. Sinev, Y.-W. Y.-W. Choi, K. Kisslinger, E. A. E. A. Stach, J. C. J. C. Yang, P. Strasser, et al., *Nat. Commun.* **2016**, *7*, 12123.

S. Lee, D. Kim, J. Lee, Angew. Chemie 2015, 127, 14914–14918.

A. Eilert, F. Cavalca, F. S. Roberts, J. Osterwalder, C. Liu, M.
 Favaro, E. J. Crumlin, H. Ogasawara, D. Friebel, L. G. M.
 Pettersson, et al., *J. Phys. Chem. Lett.* **2017**, *8*, 285–290.

[13]

- M. Favaro, H. Xiao, T. Cheng, W. A. Goddard, J. Yano, E. J.
 Crumlin, *Proc. Natl. Acad. Sci. U. S. A.* 2017, *114*, 6706–6711.
- [16] H. Xiao, W. A. Goddard, T. Cheng, Y. Liu, Proc. Natl. Acad. Sci. 2017, 201702405.
- [17] I. Platzman, R. Brener, H. Haick, R. Tannenbaum, J. Phys. Chem. C 2008, 112, 1101–1108.

[18] L. Xu, Y. Yang, Z.-W. Hu, S.-H. Yu, ACS Nano 2016, 10, 3823–3834.

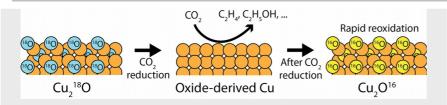
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- [19] S. Matsnnaga, T. Homma, Oxid. Met. **1976**, *10*, 361–376.
- [20] C. Gattinoni, A. Michaelides, Surf. Sci. Rep. 2015, 70, 424–447.
- [21] K. Fujita, D. Ando, M. Uchikoshi, K. Mimura, M. Isshiki, *Appl. Surf. Sci.* 2013, 276, 347–358.
- [22] Q. Zhu, L. Zou, G. Zhou, W. A. Saidi, J. C. Yang, Surf. Sci. 2016, 652, 98–113.
- [23] A. Paul, T. Laurila, V. Vuorinen, S. V Divinski, in (Eds.: A. Paul, T. Laurila, V. Vuorinen, S. V Divinski), Springer International
 Publishing, Cham, **2014**, pp. 429–491.
- [24] F. S. Roberts, K. P. Kuhl, A. Nilsson, Angew. Chemie 2015, 127, 5268–5271.
- [25] C. W. Li, J. Ciston, M. W. Kanan, *Nature* **2014**, *508*, 504–507.
- [26] A. Verdaguer-Casadevall, C. W. Li, T. P. Johansson, S. B. Scott, J.
 T. McKeown, M. Kumar, I. E. L. Stephens, M. W. Kanan, I.
 Chorkendorff, J. Am. Chem. Soc. 2015, 137, 9808–9811.
- [27] X. Feng, K. Jiang, S. Fan, M. W. Kanan, ACS Cent. Sci. 2016, 2, 169–174.

Layout 2:

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In this work, we show that residual oxides in oxide-derived Cu catalysts are not stable under strongly reducing potentials during electrochemical CO_2 reduction. This is demonstrated with the use of ¹⁸O labelled oxide-derived Cu catalysts. Instead we find that the surface is rapidly reoxidized in the absence of a reducing potential.

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